

**Search Notes**

Application/Control No.

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Examiner

John Q. Nguyen

Applicant(s)/Patent under  
Reexamination

BAYER ET AL.

Art Unit

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**SEARCHED**

Class	Subclass	Date	Examiner
Previous	search updated	2/27/06	JN
242	397	2/27/06	JN

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
PGPUB text search, see interference search printout		2/27/2006	JN

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR